FAIRCHILD

FDD6670S

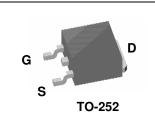
30V N-Channel PowerTrench[®] SyncFET[™]

General Description

The FDD6670S is designed to replace a single MOSFET and Schottky diode in synchronous DC:DC power supplies. This 30V MOSFET is designed to maximize power conversion efficiency, providing a low R_{DS(ON)} and low gate charge. The FDD6670S includes an integrated Schottky diode using Fairchild's monolithic SyncFET technology. The performance of the FDD6670S as the low-side switch in a synchronous rectifier is indistinguishable from the performance of the FDD6670A in parallel with a Schottky diode.

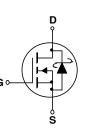
Applications

- DC/DC converter
- Motor Drives



Features

- 64 A, 30 V $R_{DS(ON)} = 9 \ m\Omega \ @ \ V_{GS} = 10 \ V$ $R_{DS(ON)} = 12.5 \ m\Omega \ @ \ V_{GS} = 4.5 \ V$
- Includes SyncFET Schottky body diode
- Low gate charge (17nC typical)
- + High performance trench technology for extremely low $R_{\text{DS}(\text{ON})}$
- High power and current handling capability



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		30	V
V _{GSS}	Gate-Source Voltage		±20	V
I _D	Drain Current – Continuous	(Note 3)	64	А
	- Pulsed	(Note 1a)	100	
P _D Powe	Power Dissipation	(Note 1)	70	W
		(Note 1a)	3.2	
		(Note 1b)	1.3	
T _J , T _{STG}	Operating and Storage Junction Temperature	e Range	-55 to +150	°C
Therma	I Characteristics			
R _{eJC}	Thermal Resistance, Junction-to-Case	(Note 1)	1.8	°C/W
R _{eJA}	Thermal Resistance, Junction-to-Ambient	(Note 1a)	40	°C/W
• •0JA		(Note 1b)	96	°C/W

Device Marking	Device	Reel Size	Tape width	Quantity
FDD6670S	FDD6670S	13"	16mm	2500 units

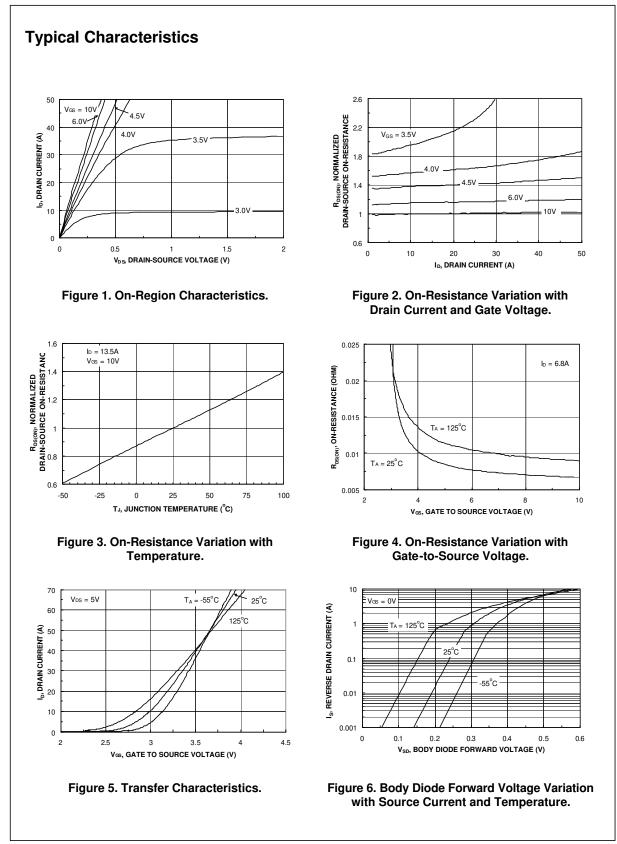
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wree Avelenche Betinge	Test Conditions	Min	Тур	Max	Units
Durce Avalanche Ratings (Note	e 2)				L
Drain-Source Avalanche Energy	Single Pulse, $V_{DD} = 15 \text{ V}$, $I_D = 14 \text{ A}$			245	mJ
Drain-Source Avalanche Current				14	Α
racteristics	•	•			
Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 1 mA$	30			V
Breakdown Voltage Temperature Coefficient	$I_D = 10$ mA, Referenced to 25°C		19		mV/°C
Zero Gate Voltage Drain Current	$V_{DS} = 24 V$, $V_{GS} = 0 V$			500	μA
Gate-Body Leakage, Forward	$V_{GS} = 20 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
acteristics (Note 2)	•	•			
, ,	$V_{DS} = V_{GS}$, $I_{D} = 1 \text{ mA}$	1	2	3	V
Gate Threshold Voltage Temperature Coefficient	$I_D = 10$ mA, Referenced to 25°C		-3.3		mV/°C
Static Drain–Source On–Resistance			6 9 10	9 12.5 15	mΩ
On-State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 5 \text{ V}$	50			Α
Forward Transconductance	$V_{DS} = 15 \text{ V}, \qquad I_{D} = 13.8 \text{ A}$		27		S
Characteristics	· ·				
	$V_{DS} = 15 V$, $V_{CS} = 0 V$.		2010		pF
Output Capacitance	f = 1.0 MHz	-	526		pF
Reverse Transfer Capacitance	1		186		pF
ř	$V_{\rm DS} = 15 \text{ V}$ $l_{\rm D} = 1 \text{ A}$		10	18	ns
,	$V_{\rm GS} = 10 \text{ V}, \qquad R_{\rm GEN} = 6 \Omega$				ns
Turn-Off Delay Time	-		34	55	ns
Turn–Off Fall Time	-		14	23	ns
Total Gate Charge	$V_{DS} = 15 \text{ V}.$ $I_{D} = 13.8 \text{ A}.$		17	24	nC
Gate-Source Charge	$V_{GS} = 10 \text{ V}$		6.2		nC
Gate-Drain Charge	1		5.5		nC
ource Diode Characteristics			I	I	
Drain–Source Diode Forward	$V_{GS} = 0 V, I_{S} = 3.5 A$ (Note 2)		0.49 0.56	0.7	V
	$V_{cc} = () V I_c = (A (Note 2))$				
Voltage Diode Reverse Recovery Time	$V_{GS} = 0 V, I_S = 7 A$ (Note 2) $I_F = 3.5 A,$		20		nS
	Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage, Forward Gate-Body Leakage, Reverse acteristics (Note 2) Gate Threshold Voltage Gate Threshold Voltage Temperature Coefficient Static Drain-Source On-Resistance On-State Drain Current Forward Transconductance Characteristics Input Capacitance Output Capacitance Reverse Transfer Capacitance g Characteristics (Note 2) Turn-On Delay Time Turn-On Rise Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	CoefficientVZero Gate Voltage Drain Current $V_{DS} = 24 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage, Forward $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage, Reverse $V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$ acteristics (Note 2)(Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 1 \text{ mA}$ Gate Threshold Voltage $I_D = 10 \text{ mA}$, Referenced to 25°CTemperature Coefficient $I_D = 10 \text{ mA}$, Referenced to 25°CStatic Drain-Source $V_{GS} = 10 \text{ V}$, $I_D = 13.8 \text{ A}$ On-Resistance $V_{GS} = 10 \text{ V}$, $I_D = 13.8 \text{ A}$ On-Resistance $V_{GS} = 10 \text{ V}$, $V_{DS} = 5 \text{ V}$ Forward Transconductance $V_{DS} = 15 \text{ V}$, $I_D = 13.8 \text{ A}$ Characteristics Input CapacitanceInput Capacitance $V_{DS} = 15 \text{ V}$, $V_{GS} = 0 \text{ V}$,Output Capacitance $V_{DS} = 15 \text{ V}$, $V_{GS} = 0 \text{ V}$,furm-On Delay Time $V_{DS} = 15 \text{ V}$, $I_D = 1 \text{ A}$,Turm-On Rise Time $V_{GS} = 10 \text{ V}$, $R_{GEN} = 6 \Omega$ Turm-Off Fall Time $V_{DS} = 15 \text{ V}$, $I_D = 13.8 \text{ A}$,V_{GS} = 10 V $V_{GS} = 10 \text{ V}$	CoefficientV USV USV USV USV USZero Gate Voltage Drain Current $V_{DS} = 24$ V, $V_{DS} = 0$ VVGate-Body Leakage, Forward $V_{GS} = 20$ V, $V_{DS} = 0$ VVGate-Body Leakage, Reverse $V_{GS} = -20$ V, $V_{DS} = 0$ VVacteristics (Note 2)Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 1$ mA1Gate Threshold Voltage $I_D = 10$ mA, Referenced to 25°CVTemperature Coefficient $I_D = 10$ mA, Referenced to 25°CVStatic Drain-Source $V_{GS} = 10$ V, $I_D = 13.8$ AVOn-Resistance $V_{GS} = 10$ V, $I_D = 13.8$ A, $I_J = 125°C$ OOn-State Drain Current $V_{GS} = 10$ V, $V_{DS} = 5$ V50Forward Transconductance $V_{DS} = 15$ V, $I_D = 13.8$ ASCharacteristicsInput Capacitance $V_{DS} = 15$ V, $V_{GS} = 0$ V, $I_D = 120$ VInput Capacitance $V_{DS} = 15$ V, $V_{CS} = 0$ V, $I_D = 10$ MHzImput Capacitancerum-On Delay Time $V_{DS} = 15$ V, $V_{CS} = 10$ V, $R_{GEN} = 6$ Ω Imput CapacitanceTurm-On Rise Time $V_{DS} = 15$ V, $I_D = 13.8$ A, $V_{CS} = 10$ V, $V_{CS} = 10$ VImput CapacitanceTurn-Off Fall Time $V_{DS} = 15$ V, $I_D = 13.8$ A, $V_{CS} = 10$ VImput Capacitance	$\begin{tabular}{ c c c c c c } \hline Coefficient & V_{DS} = 24 V, & V_{GS} = 0 V & \\ \hline Zero Gate Voltage Drain Current & V_{DS} = 20 V, & V_{DS} = 0 V & \\ \hline Gate-Body Leakage, Forward & V_{GS} = 20 V, & V_{DS} = 0 V & \\ \hline Gate-Body Leakage, Reverse & V_{GS} = -20 V, & V_{DS} = 0 V & \\ \hline Gate Thresholy Leakage, Reverse & V_{GS} = -20 V, & V_{DS} = 0 V & \\ \hline Catteristics & (Note 2) & \\ \hline Gate Threshold Voltage & V_{DS} = V_{GS}, & l_{D} = 1 mA & 1 & 2 & \\ \hline Gate Threshold Voltage & l_{D} = 10 mA, Referenced to 25^{\circ}C & -3.3 & \\ \hline Temperature Coefficient & l_{D} = 10 W, & l_{D} = 13.8 A & 6 & \\ On-Resistance & V_{GS} = 10 V, & l_{D} = 13.8 A, & f_{U} = 125^{\circ}C & 10 & \\ On-State Drain Current & V_{GS} = 10 V, & V_{DS} = 5 V & 50 & \\ \hline Con-State Drain Current & V_{GS} = 10 V, & V_{DS} = 5 V & 50 & \\ \hline Forward Transconductance & V_{DS} = 15 V, & l_{D} = 13.8 A & 27 & \\ \hline Characteristics & \\ Input Capacitance & V_{DS} = 15 V, & V_{GS} = 0 V, & 2010 & \\ Output Capacitance & f = 1.0 MHz & 526 & \\ \hline Reverse Transfer Capacitance & \\ \hline Turm-On Delay Time & V_{DS} = 15 V, & l_{D} = 1 A, & 10 & \\ Turm-Off Delay Time & V_{DS} = 15 V, & l_{D} = 1 A, & 10 & \\ Turm-Off Delay Time & V_{DS} = 15 V, & l_{D} = 1 A, & 10 & \\ \hline Turm-Off Fall Time & & V_{CS} = 10 V, & R_{GEN} = 6 & \Omega & 10 & \\ \hline Turm-Off Fall Time & & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Gate-Source Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17 & \\ \hline Cate Gate Charge & V_{DS} = 15 V, & l_{D} = 13.8 A, & 17$	$\begin{array}{ c c c c c c c c c c c c c c c c c c c$

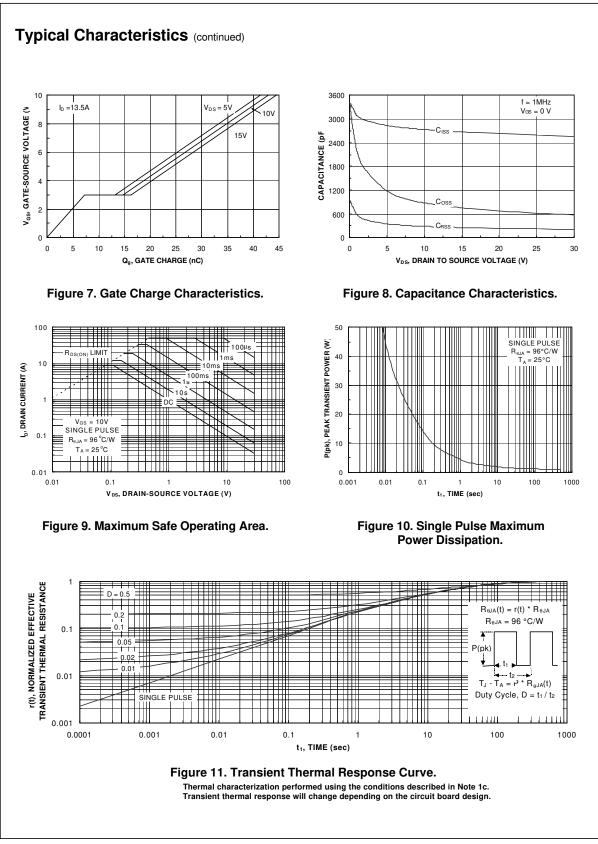
FDD6670S

FDD6670S Rev E (W)

Electrical Characteris	stics	T _A = 25°C unless otherwis	e noted		-
Notes: 1. R _{6JA} is the sum of the junction-to-case and the drain pins. R _{6JC} is guaranteed by des	l case-to-ambient tl ign while R _{θCA} is d	hermal resistance where the ca etermined by the user's board	se thermal reference design.	is defined as the solder r	nounting surface of
=	a) R _{0JA} = 40°C/ 1in ² pad of	/W when mounted on a 2 oz copper	■:	b) R_{6JA} = 96°C/W whe on a minimum pad	n mounted
Scale 1 : 1 on letter size paper					
2. Pulse Test: Pulse Width < 300µs, Duty Cy	cle < 2.0%				
3. Maximum current is calculated as: where P_D is maximum power dissipation	$\frac{P_{D}}{R_{DS(ON)}}$ at T _C = 25°C and	$R_{DS(on)}$ is at $T_{J(max)}$ and V_{GS} = 1	0V. Package curre	nt limitation is 21A	
					FDD6670S Rev E (W)



FDD6670S



FDD6670S

FDD6670S Rev E (W)

Typical Characteristics (continued)

SyncFET Schottky Body Diode Characteristics

Fairchild's SyncFET process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 12 shows the reverse recovery characteristic of the FDD6670S.

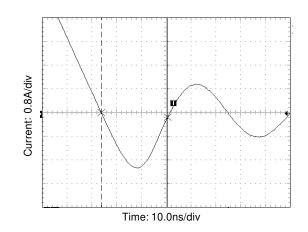


Figure 12. FDD6670S SyncFET body diode reverse recovery characteristic.

For comparison purposes, Figure 13 shows the reverse recovery characteristics of the body diode of an equivalent size MOSFET produced without SyncFET (FDD6670A).

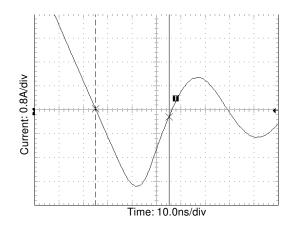


Figure 13. Non-SyncFET (FDD6670A) body diode reverse recovery characteristic.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.

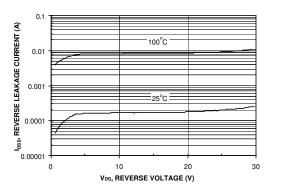


Figure 14. SyncFET body diode reverse leakage versus drain-source voltage and temperature.



FDD6670S

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